

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/326,285	<b>Applicant(s)/Patent under Reexamination</b> SHEN, JENNIE BIH-JIEN
	<b>Examiner</b> Elizabeth F. McElwain	<b>Art Unit</b> 1638

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
426	635	5/31/2005	EM
800	281		